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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	EBI/EMI, I²C, IrDA, SmartCard, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	65
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 32x12b; D/A 2x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	80-TQFP
Supplier Device Package	80-TQFP (12x12)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/sim3u167-b-gqr

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2. Typical Connection Diagrams

This section provides typical connection diagrams for SiM3C1xx devices.

2.1. Power

Figure 2.1 shows a typical connection diagram for the power pins of the SiM3C1xx devices when the internal regulator is in use.

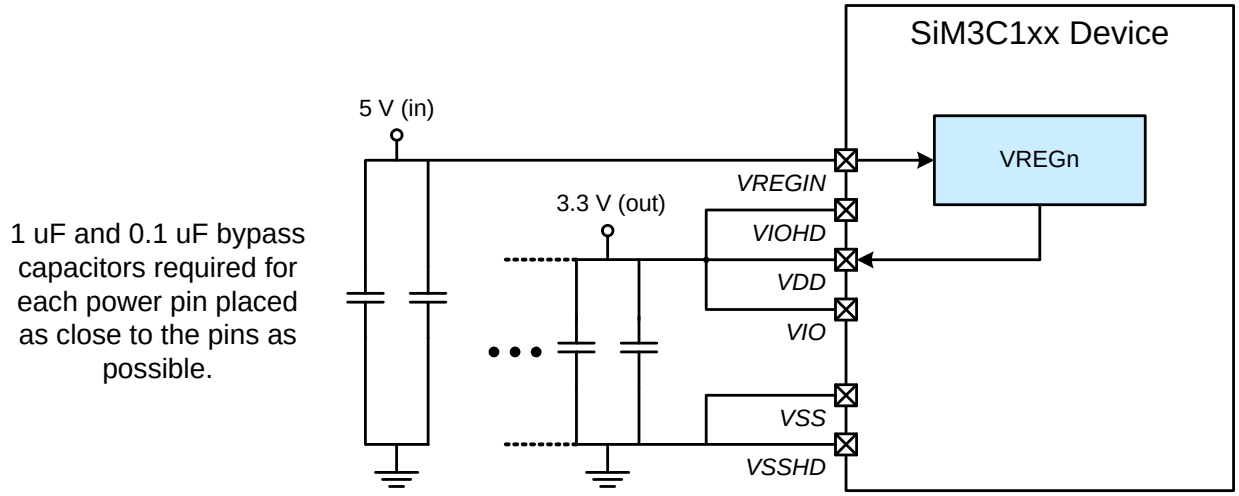

Figure 2.1. Connection Diagram with Voltage Regulator Used

Figure 2.2 shows a typical connection diagram for the power pins of the SiM3C1xx devices when the internal regulator is not used.

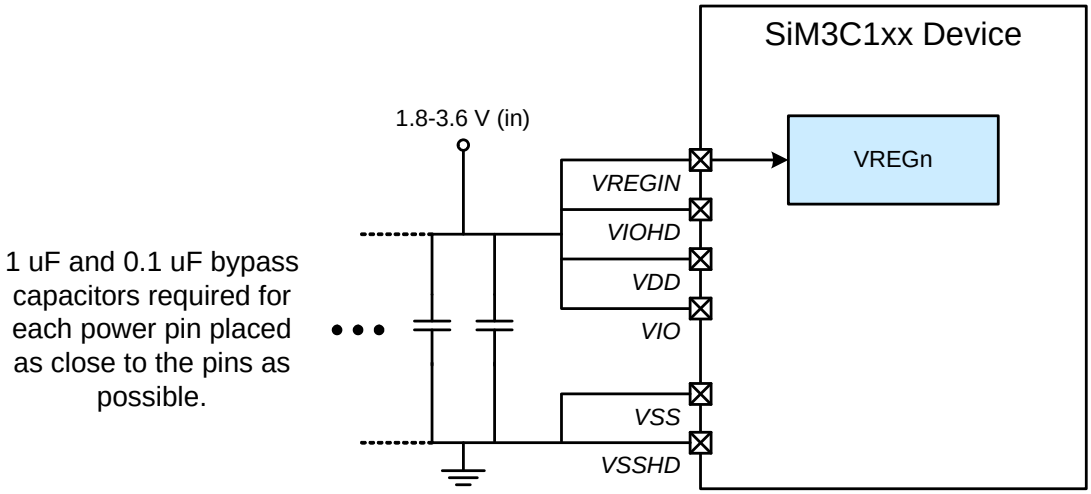

Figure 2.2. Connection Diagram with Voltage Regulator Not Used

Table 3.2. Power Consumption (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Power Mode 9[2,3]—Low Power Shutdown with VREG0 disabled, powered through VDD and VIO	I_{DD}	RTC Disabled, V_{DD} = 1.8 V, T_A = 25 °C	—	85	—	nA
		RTC w/ 16.4 kHz LFO, V_{DD} = 1.8 V, T_A = 25 °C	—	350	—	nA
		RTC w/ 32.768 kHz Crystal, V_{DD} = 1.8 V, T_A = 25 °C	—	620	—	nA
		RTC Disabled, V_{DD} = 3.0 V, T_A = 25 °C	—	145	—	nA
		RTC w/ 16.4 kHz LFO, V_{DD} = 3.0 V, T_A = 25 °C	—	500	—	nA
		RTC w/ 32.768 kHz Crystal, V_{DD} = 3.0 V, T_A = 25 °C	—	800	—	nA
Power Mode 9[2,3]—Low Power Shutdown with VREG0 in low-power mode, VDD and VIO powered through VREG0 (Includes VREG0 current)	I_{VREGIN}	RTC Disabled, VREGIN = 5 V, T_A = 25 °C	—	300	—	nA
		RTC w/ 16.4 kHz LFO, VREGIN = 5 V, T_A = 25 °C	—	650	—	nA
		RTC w/ 32.768 kHz Crystal, VREGIN = 5 V, T_A = 25 °C	—	950	—	nA
VIOHD Current (High-drive I/O disabled)	I_{VIOHD}	HV Mode (default)	—	2.5	5	µA
		LV Mode	—	2	—	nA

Notes:

1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.2. Power Consumption (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Oscillator (EXTOSC0)[8]	I_{EXTOSC}	FREQCN = 111	—	3.8	4.7	mA
		FREQCN = 110	—	840	950	µA
		FREQCN = 101	—	185	220	µA
		FREQCN = 100	—	65	80	µA
		FREQCN = 011	—	25	30	µA
		FREQCN = 010	—	10	15	µA
		FREQCN = 001	—	5	10	µA
		FREQCN = 000	—	3	8	µA
SARADC0, SARADC1	I_{SARADC}	Sampling at 1 Msps, highest power mode settings.	—	1.2	1.5	mA
		Sampling at 250 ksps, lowest power mode settings.	—	390	510	µA
Temperature Sensor	I_{TSENSE}		—	75	105	µA
Internal SAR Reference	I_{REFFS}	Normal Power Mode	—	680	750	µA
		Low Power Mode	—	160	190	µA
VREF0	I_{REFP}		—	75	100	µA
Comparator 0 (CMP0), Comparator 1 (CMP1)	I_{CMP}	CMPMD = 11	—	0.5	—	µA
		CMPMD = 10	—	3	—	µA
		CMPMD = 01	—	10	—	µA
		CMPMD = 00	—	25	—	µA
Capacitive Sensing (CAPSENSE0)	I_{CS}	Continuous Conversions	—	55	80	µA
IDAC0[7], IDAC1[7]	I_{IDAC}		—	75	90	µA
IVC0[7]	I_{IVC}	I_{IN} = 0	—	1.5	2.5	µA
Voltage Supply Monitor (VMON0)	I_{VMON}		—	15	25	µA

Notes:

1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.2. Power Consumption (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Flash Current on VDD						
Write Operation	$I_{FLASH-W}$		—	—	8	mA
Erase Operation	$I_{FLASH-E}$		—	—	15	mA

Notes:
1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.3. Power Mode Wake Up Times

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Power Mode 2 Wake Time	t_{PM2}		4	—	5	clocks
Power Mode 3 Fast Wake Time	t_{PM3FW}		—	425	—	µs
Power Mode 9 Wake Time	t_{PM9}		—	12	—	µs

Table 3.10. SAR ADC (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Differential Nonlinearity (Guaranteed Monotonic)	DNL	12 Bit Mode[2]	–1	±0.7	1.8	LSB
		10 Bit Mode	—	±0.2	±0.5	LSB
Offset Error (using VREFGND)	E_{OFF}	12 Bit Mode, VREF =2.4 V	–2	0	2	LSB
		10 Bit Mode, VREF =2.4 V	–1	0	1	LSB
Offset Temperatue Coefficient	TC_{OFF}		—	0.004	—	LSB/°C
Slope Error[3]	E_M	12 Bit Mode	–0.07	–0.02	0.02	%
Dynamic Performance with 10 kHz Sine Wave Input 1 dB below full scale, Max throughput						
Signal-to-Noise	SNR	12 Bit Mode	62	66	—	dB
		10 Bit Mode	58	60	—	dB
Signal-to-Noise Plus Distortion	SNDR	12 Bit Mode	62	66	—	dB
		10 Bit Mode	58	60	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD	12 Bit Mode	—	78	—	dB
		10 Bit Mode	—	77	—	dB
Spurious-Free Dynamic Range	SFDR	12 Bit Mode	—	–79	—	dB
		10 Bit Mode	—	–74	—	dB

Notes:
1. Absolute input pin voltage is limited by the lower of the supply at VDD and VIO.
2. INL and DNL specifications for 12-bit mode do not include the first or last four ADC codes.
3. The maximum code in 12-bit mode is 0xFFFC. The Slope Error is referenced from the maximum code.

3.2. Thermal Conditions

Table 3.18. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance*	θ_{JA}	LGA-92 Packages	—	35	—	°C/W
		TQFP-80 Packages	—	40	—	°C/W
		QFN-64 Packages	—	25	—	°C/W
		TQFP-64 Packages	—	30	—	°C/W
		QFN-40 Packages	—	30	—	°C/W
***Note:** Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.						

3.3. Absolute Maximum Ratings

Stresses above those listed under Table 3.19 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 3.19. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		–55	125	°C
Storage Temperature	T_{STG}		–65	150	°C
Voltage on VDD	V_{DD}		V_{SS}–0.3	4.2	V
Voltage on VREGIN	V_{REGIN}	EXTVREG0 Not Used	V_{SS}–0.3	6.0	V
		EXTVREG0 Used	V_{SS}–0.3	3.6	V
Voltage on VIO	V_{IO}		V_{SS}–0.3	4.2	V
Voltage on VIOHD	V_{IOHD}		V_{SS}–0.3	6.5	V
Voltage on I/O pins, non Port Bank 3 I/O	V_{IN}	$\overline{\text{RESET}}$, $V_{IO} \geq 3.3$ V	V_{SS}–0.3	5.8	V
		$\overline{\text{RESET}}$, $V_{IO} < 3.3$ V	V_{SS}–0.3	V_{IO}+2.5	V
		Port Bank 0, 1, and 2 I/O	V_{SS}–0.3	V_{IO}+0.3	V
		Port Bank 4 I/O	V_{SSHD}–0.3	V_{IOHD}+0.3	V
***Note:** VSS and VSSHD provide separate return current paths for device supplies, but are not isolated. They must always be connected to the same potential on board.					

volatile data storage and allowing field upgrades of the firmware. User firmware has complete control of all peripherals and may individually shut down and gate the clocks of any or all peripherals for power savings.

The on-chip debugging interface (SWJ-DP) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging.

Each device is specified for 1.8 to 3.6 V operation over the industrial temperature range (–40 to +85 °C). The Port I/O and RESET pins are powered from the IO supply voltage. The SiM3C1xx devices are available in 40-pin or 64-pin QFN, 64-pin or 80-pin TQFP, or 92-pin LGA packages. All package options are lead-free and RoHS compliant. See Table 5.1 for ordering information. A block diagram is included in Figure 4.1.

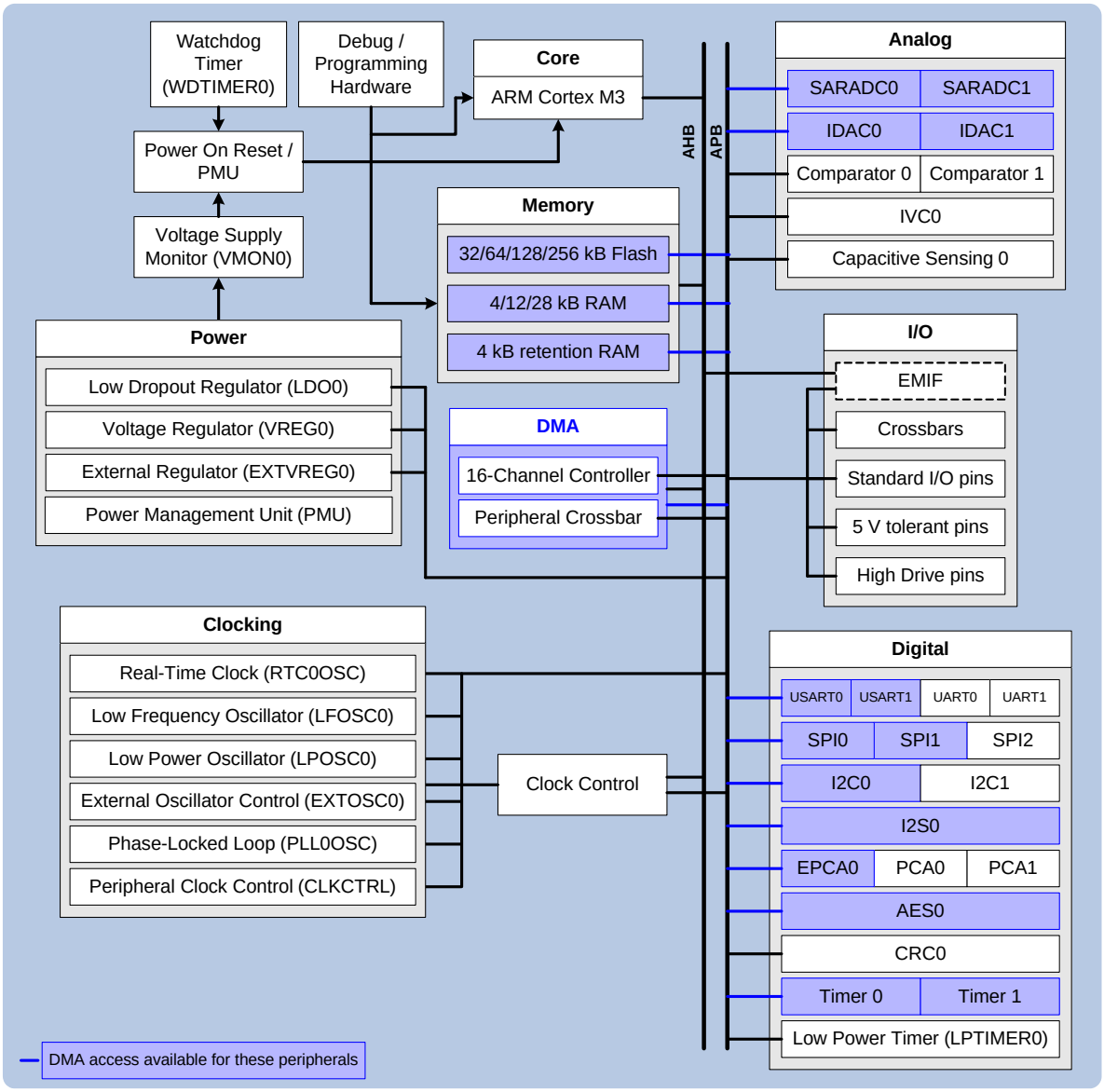

Figure 4.1. Precision32™ SiM3C1xx Family Block Diagram

4.1.5. Device Power Modes

The SiM3C1xx devices feature four low power modes in addition to normal operating mode. Several peripherals provide wake up sources for these low power modes, including the Low-Power Timer (LPT0), RTC0 (alarms and oscillator failure notification), Comparator 0, and PMU Pin Wake.

In addition, all peripherals can have their clocks disabled to reduce power consumption whenever a peripheral is not being used using the clock control (CLKCTRL) registers.

4.1.5.1. Normal Mode (Power Mode 0)

Normal Mode is the default mode of the device. The core and peripherals are fully operational, and instructions are executed from flash memory.

4.1.5.2. Power Mode 1

In Power Mode 1 the core and peripherals are fully operational, with instructions executing from RAM. Compared with Normal Mode, the active power consumption of the device in PM1 is reduced. Additionally, at higher speeds in PM1, the core throughput can also be increased because RAM does not require additional wait states that reduce the instruction fetch speed.

4.1.5.3. Power Mode 2

In Power Mode 2 the core halts and any enabled peripherals continue to run at the selected clock speed. The power consumption in PM2 corresponds to the AHB and APB clocks left enabled, thus the power can be tuned to the optimal level for the needs of the application. To place the device in PM2, the core should execute a wait-for-interrupt (WFI) or wait-for-event (WFE) instruction. If the WFI instruction is called from an interrupt service routine, the interrupt that wakes the device from PM2 must be of a sufficient priority to be recognized by the core. It is recommended to perform both a DSB (Data Synchronization Barrier) and an ISB (Instruction Syncronization Barrier) operation prior to the WFI to ensure all bus accesses complete. When operating from the LFOSC0 with the DMACTRL0 AHB clock disabled, PM2 can achieve similar power consumption to PM3, but with the ability to wake on APB-clocked interrupts. For example, enabling only the APB clock to the Ports will allow the firmware to wake on a PMATCH0, PBEXT0 or PBEXT1 interrupt with minimal impact on the supply current.

4.1.5.4. Power Mode 3

In Power Mode 3, the AHB and APB clocks are halted. The device may only wake from enabled interrupt sources which do not require the APB clock (RTC0ALRM, RTC0FAIL, LPTIMER0, VDDLOW and VREGLOW). A special fast wake option allows the device to operate at a very low level from the RTC0TCLK or LFOSC0 oscillator while in PM3, but quickly switch to the faster LPOSC0 when the wake event occurs. Because the current consumption of these blocks is minimal, it is recommended to use the fast wake option.

The device will enter PM3 on a WFI or WFE instruction. Because all AHB master clocks are disabled, the LPOSC will automatically halt and go into a low-power suspended state. If the WFI instruction is called from an interrupt service routine, the interrupt that wakes the device from PM3 must be of a sufficient priority to be recognized by the core. It is recommended to perform both a DSB (Data Synchronization Barrier) and an ISB (Instruction Synchronization Barrier) operation prior to the WFI to ensure all bus access is complete.

4.1.5.5. Power Mode 9

In Power Mode 9, the core and all peripherals are halted, all clocks are stopped, and the pins and peripherals are set to a lower power mode. In addition, standard RAM contents are not preserved, though retention RAM contents are still available after exiting the power mode. This mode provides the lowest power consumption for the device, but requires an appropriate reset to exit. The available reset sources to wake from PM9 are controlled by the Power Management Unit (PMU).

Before entering PM9, the desired reset source(s) should be configured in the PMU. The SLEEPDEEP bit in the ARM System Control Register should be set, and the PMSEL bit in the RSTSRC0_CONFIG register must be set to indicate that PM9 is the desired power mode.

The device will enter PM9 on a WFI or WFE instruction, and remain in PM9 until a reset configured by the PMU occurs. It is recommended to perform both a DSB (Data Synchronization Barrier) and an ISB (Instruction Synchronization Barrier) operation prior to the WFI to ensure all bus access is complete.

4.3.1. PLL (PLL0)

The PLL module consists of a dedicated Digitally-Controlled Oscillator (DCO) that can be used in Free-Running mode without a reference frequency, Frequency-Locked to a reference frequency, or Phase-Locked to a reference frequency. The reference frequency for Frequency-Lock and Phase-Lock modes can use one of multiple sources (including the external oscillator) to provide maximum flexibility for different application needs. Because the PLL module generates its own clock, the DCO can be locked to a particular reference frequency and then moved to Free-Running mode to reduce system power and noise.

The PLL module includes the following features:

- Five output ranges with output frequencies ranging from 23 to 80 MHz.
- Multiple reference frequency inputs.
- Three output modes: free-running DCO, frequency-locked, and phase-locked.
- Ability to sense the rising edge or falling edge of the reference source.
- DCO frequency LSB dithering to provide finer average output frequencies.
- Spectrum spreading to reduce generated system noise.
- Low jitter and fast lock times.
- Ability to suspend all output frequency updates (including dithering and spectrum spreading) using the STALL bit during jitter-sensitive operations.

4.3.2. Low Power Oscillator (LPOSC0)

The Low Power Oscillator is the default AHB oscillator on SiM3C1xx devices and enables or disables automatically, as needed.

The Low Power Oscillator has the following features:

- 20 MHz and divided 2.5 MHz frequencies available for the AHB clock.
- Automatically starts and stops as needed.

4.3.3. Low Frequency Oscillator (LFOSC0)

The low frequency oscillator (LFOSC0) provides a low power internal clock source running at approximately 16.4 kHz for the RTC0 timer and other peripherals on the device. No external components are required to use the low frequency oscillator

4.3.4. External Oscillators (EXTOSC0)

The EXTOSC0 external oscillator circuit may drive an external crystal, ceramic resonator, capacitor, or RC network. A CMOS clock may also provide a clock input. The external oscillator output may be selected as the AHB clock or used to clock other modules independent of the AHB clock selection.

The External Oscillator control has the following features:

- Support for external crystal, RC, C, or CMOS oscillators.
- Support external CMOS frequencies from 10 kHz to 50 MHz and external crystal frequencies from 10 kHz to 30 MHz.
- Various drive strengths for flexible crystal oscillator support.
- Internal frequency divide-by-two option available.

Table 5.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (kB)	External Memory Interface (EMIF)	Maximum Number of EMIF Address/Data Pins	Digital Port I/Os (Total)	Digital Port I/Os with High Drive Capability	Number of SARADC0 Channels	Number of SARADC1 Channels	Number of CAPSENSE0 Channels	Number of Comparator 0/1 Inputs (+/-)	Number of PMU Pin Wake Sources	JTAG Debugging Interface	ETM Debugging Interface	Serial Wire Debugging Interface	Lead-free (RoHS Compliant)	Package
SiM3C167-B-GM	256	32	✓	24	65	6	16	16	16	8/8	16	✓	✓	✓	✓	LGA-92
SiM3C167-B-GQ	256	32	✓	24	65	6	16	16	16	8/8	16	✓	✓	✓	✓	TQFP-80
SiM3C166-B-GM	256	32	✓	16	50	4	13	15	15	6/6	15	✓		✓	✓	QFN-64
SiM3C166-B-GQ	256	32	✓	16	50	4	13	15	15	6/6	15	✓		✓	✓	TQFP-64
SiM3C164-B-GM	256	32			28	4	7	11	12	3/3	10			✓	✓	QFN-40
SiM3C157-B-GM	128	32	✓	24	65	6	16	16	16	8/8	16	✓	✓	✓	✓	LGA-92
SiM3C157-B-GQ	128	32	✓	24	65	6	16	16	16	8/8	16	✓	✓	✓	✓	TQFP-80
SiM3C156-B-GM	128	32	✓	16	50	4	13	15	15	6/6	15	✓		✓	✓	QFN-64
SiM3C156-B-GQ	128	32	✓	16	50	4	13	15	15	6/6	15	✓		✓	✓	TQFP-64
SiM3C154-B-GM	128	32			28	4	7	11	12	3/3	10			✓	✓	QFN-40
SiM3C146-B-GM	64	16	✓	16	50	4	13	15	15	6/6	15	✓		✓	✓	QFN-64
SiM3C146-B-GQ	64	16	✓	16	50	4	13	15	15	6/6	15	✓		✓	✓	TQFP-64
SiM3C144-B-GM	64	16			28	4	7	11	12	3/3	10			✓	✓	QFN-40
SiM3C136-B-GM	32	8	✓	16	50	4	13	15	15	6/6	15	✓		✓	✓	QFN-64
SiM3C136-B-GQ	32	8	✓	16	50	4	13	15	15	6/6	15	✓		✓	✓	TQFP-64
SiM3C134-B-GM	32	8			28	4	7	11	12	3/3	10			✓	✓	QFN-40

Table 6.1. Pin Definitions and alternate functions for SiM3C1x7

Pin Name	Type	Pin Numbers TQFP-80	Pin Numbers LGA-92	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
VSS	Ground	33 75	B15 B34							
VDD	Power (Core)	74	A44							
VIO	Power (I/O)	32 49 73	A19 A29 A43							
VREGIN	Power (Regulator)	76	A45							
VSSHD	Ground (High Drive)	4	B2							
VIOHD	Power (High Drive)	5	A3							
$\overline{\text{RESET}}$	Active-low Reset	80	A48							
SWCLK/TCK	Serial Wire/JTAG	45	B20							
SWDIO/TMS	Serial Wire/JTAG	44	A27							
PB0.0	Standard I/O	72	B33	XBR0	✓					ADC0.0
PB0.1	Standard I/O	71	B32	XBR0	✓					ADC0.1 CS0.0
PB0.2	Standard I/O	70	A42	XBR0	✓					ADC0.2 CS0.1
PB0.3	Standard I/O	69	B31	XBR0	✓					ADC0.3 CS0.2
PB0.4	Standard I/O	68	A41	XBR0	✓					ADC0.4 CS0.3
PB0.5	Standard I/O	67	B30	XBR0	✓					ADC0.5 CS0.4
PB0.6	Standard I/O	66	A40	XBR0	✓					CS0.5
PB0.7	Standard I/O	65	B29	XBR0	✓					ADC0.6 CS0.6 IVC0.0

Table 6.1. Pin Definitions and alternate functions for SiM3C1x7 (Continued)

Pin Name	Type	Pin Numbers TQFP-80	Pin Numbers LGA-92	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
PB0.8	Standard I/O	64	A39	XBR0	✓					ADC0.7 CS0.7 IVC0.1
PB0.9	Standard I/O	63	A38	XBR0	✓					ADC0.8 RTC1
PB0.10	Standard I/O	62	A37	XBR0	✓					RTC2
PB0.11	Standard I/O	61	D4	XBR0	✓					ADC0.9 VREFGND
PB0.12	Standard I/O	60	A36	XBR0	✓					ADC0.10 VREF
PB0.13	Standard I/O	59	A35	XBR0	✓					IDAC0
PB0.14	Standard I/O	58	B27	XBR0	✓					IDAC1
PB0.15	Standard I/O	57	A34	XBR0	✓					XTAL1
PB1.0	Standard I/O	56	A33	XBR0	✓					XTAL2
PB1.1	Standard I/O	55	B25	XBR0	✓					ADC0.11
PB1.2/TRST	Standard I/O /JTAG	54	A32	XBR0	✓					
PB1.3/TDO/ SWV	Standard I/O /JTAG/ Serial Wire Viewer	53	B24	XBR0	✓					ADC0.12 ADC1.12
PB1.4/TDI	Standard I/O /JTAG	52	A31	XBR0	✓					ADC0.13 ADC1.13
PB1.5/ETM0	Standard I/O /ETM	51	B23	XBR0	✓					ADC0.14 ADC1.14
PB1.6/ETM1	Standard I/O /ETM	50	A30	XBR0	✓					ADC0.15 ADC1.15
PB1.7/ETM2	Standard I/O /ETM	48	B22	XBR0	✓					ADC1.11 CS0.8
PB1.8/ETM3	Standard I/O /ETM	47	B21	XBR0	✓					ADC1.10 CS0.9

6.2. SiM3C1x6 Pin Definitions

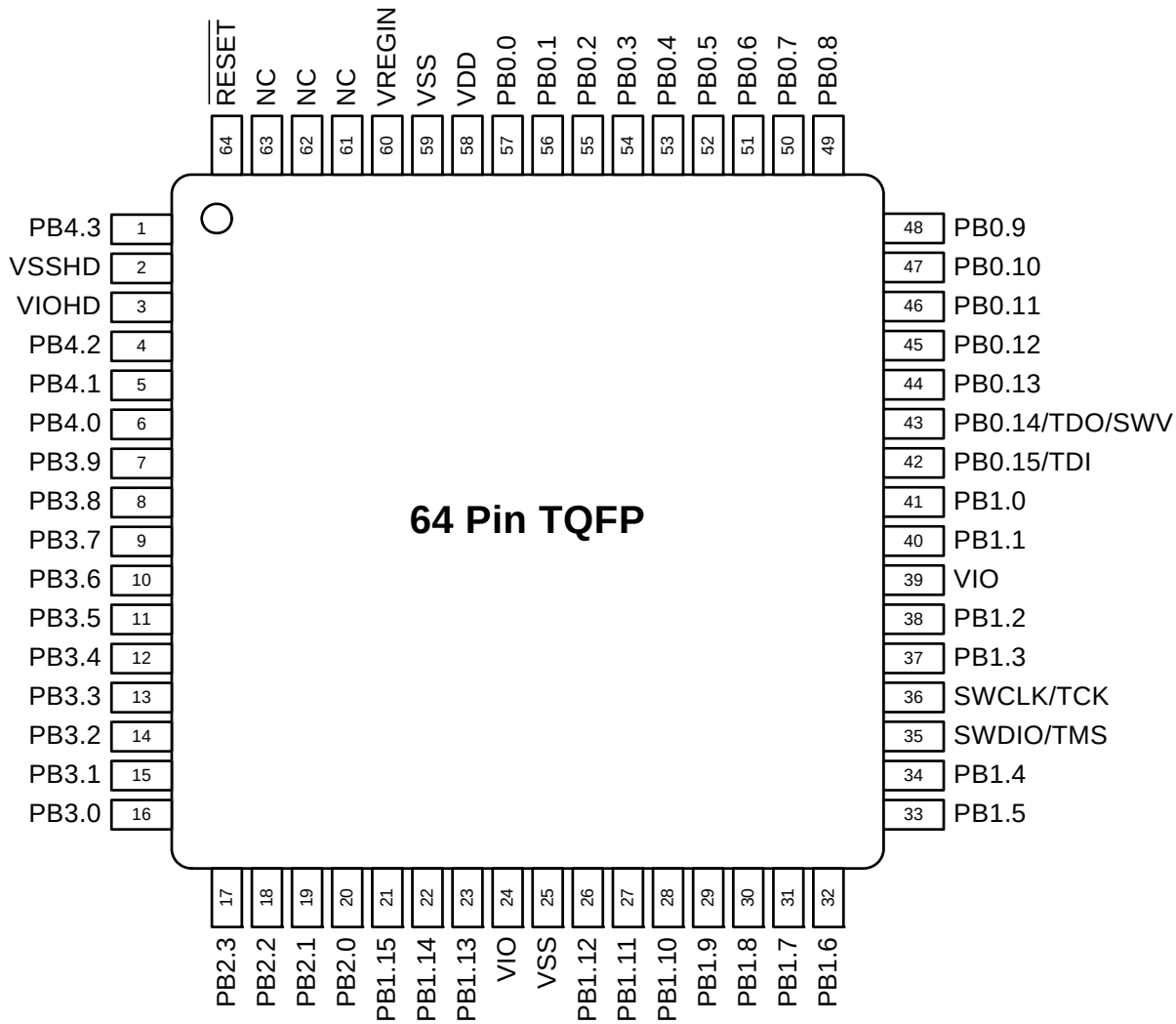

Figure 6.3. SiM3C1x6-GQ Pinout

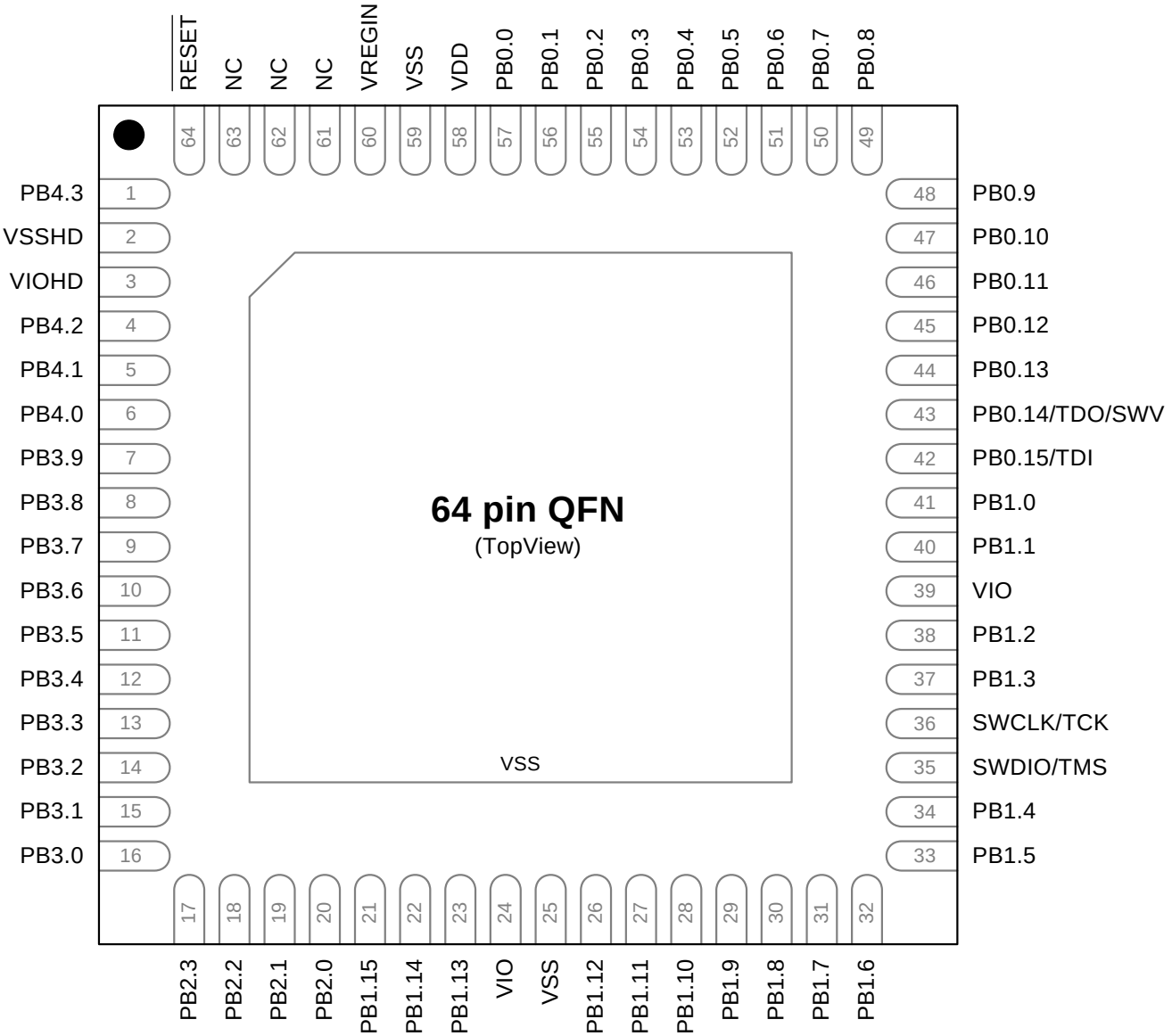

Figure 6.4. SiM3C1x6-GM Pinout

6.5. TQFP-80 Package Specifications

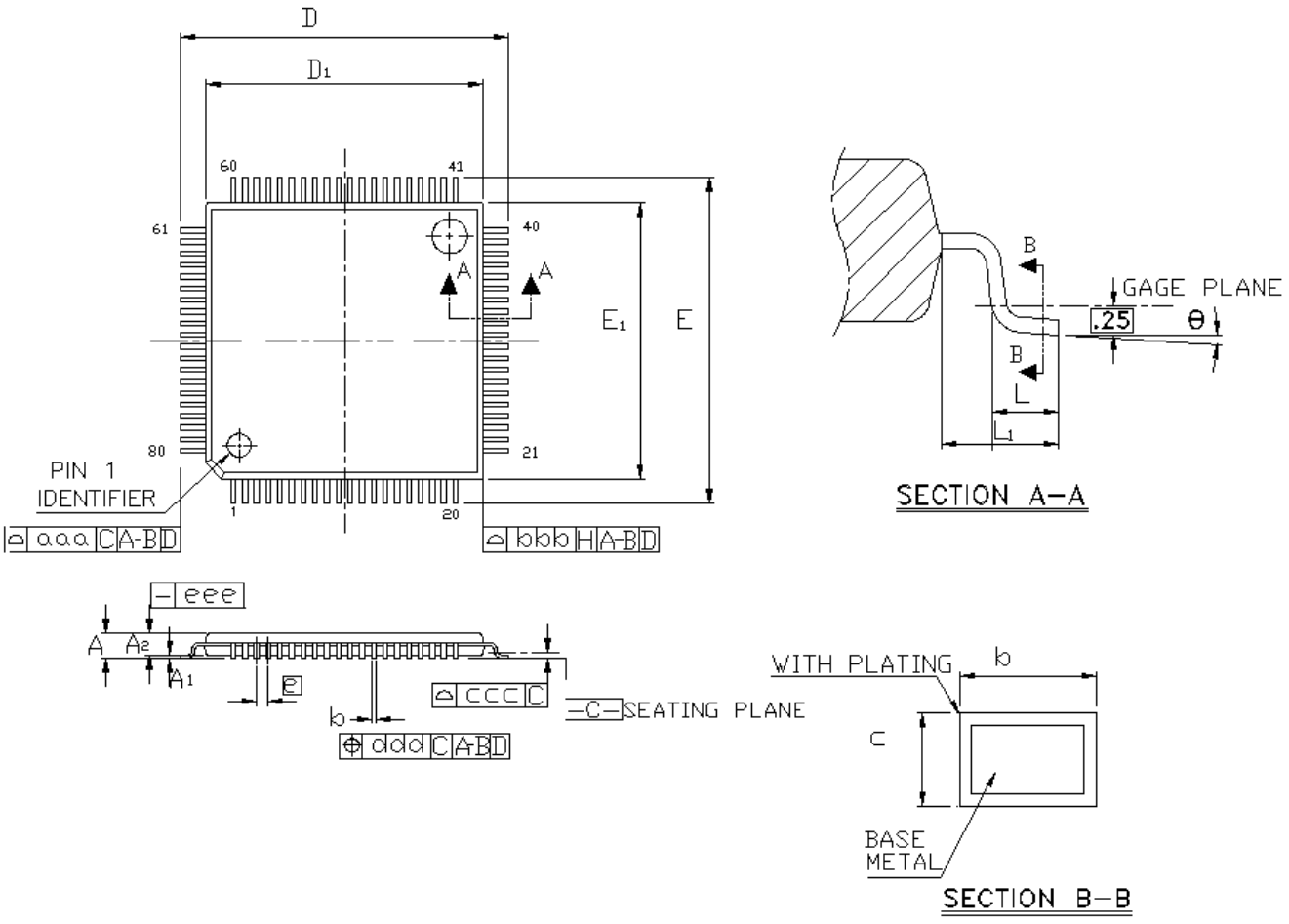

Figure 6.8. TQFP-80 Package Drawing

Table 6.6. TQFP-80 Package Dimensions

Dimension	Min	Nominal	Max
A	—	—	1.20
A1	0.05	—	0.15
A2	0.95	1.00	1.05
b	0.17	0.20	0.27
c	0.09	—	0.20
D	14.00 BSC		
D1	12.00 BSC		
e	0.50 BSC		
E	14.00 BSC		
E1	12.00 BSC		

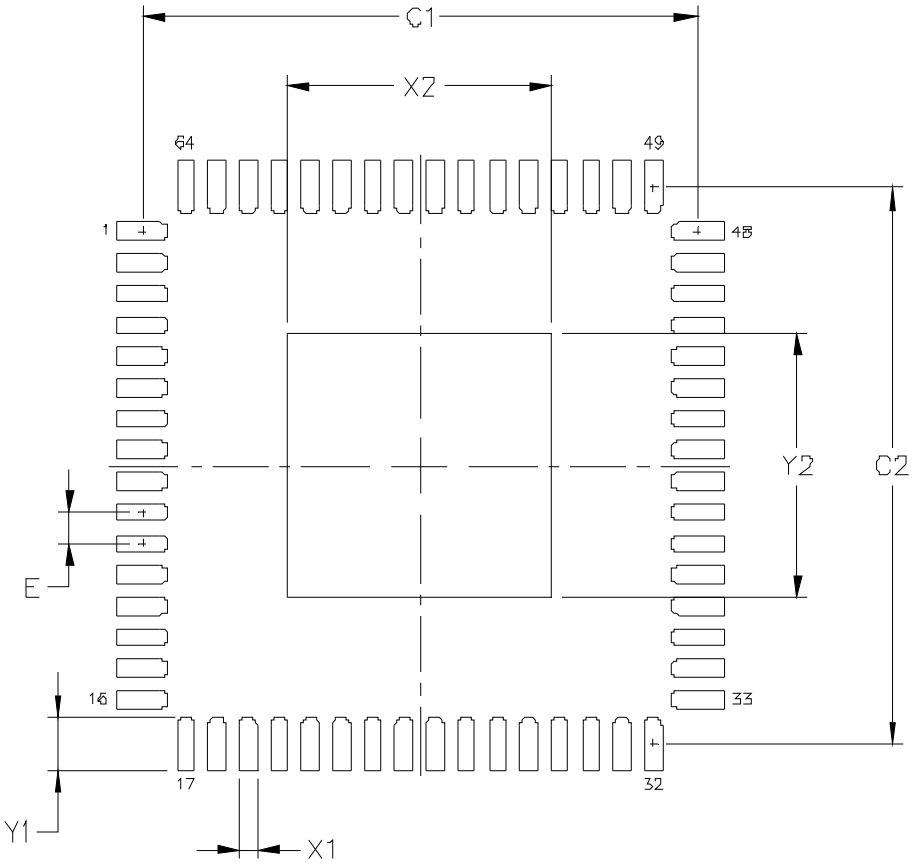

Figure 6.11. QFN-64 Landing Diagram

Table 6.9. QFN-64 Landing Diagram Dimensions

Dimension	mm
C1	8.90
C2	8.90
E	0.50
X1	0.30
Y1	0.85
X2	4.25
Y2	4.25

Notes:
1. All dimensions shown are in millimeters (mm).
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

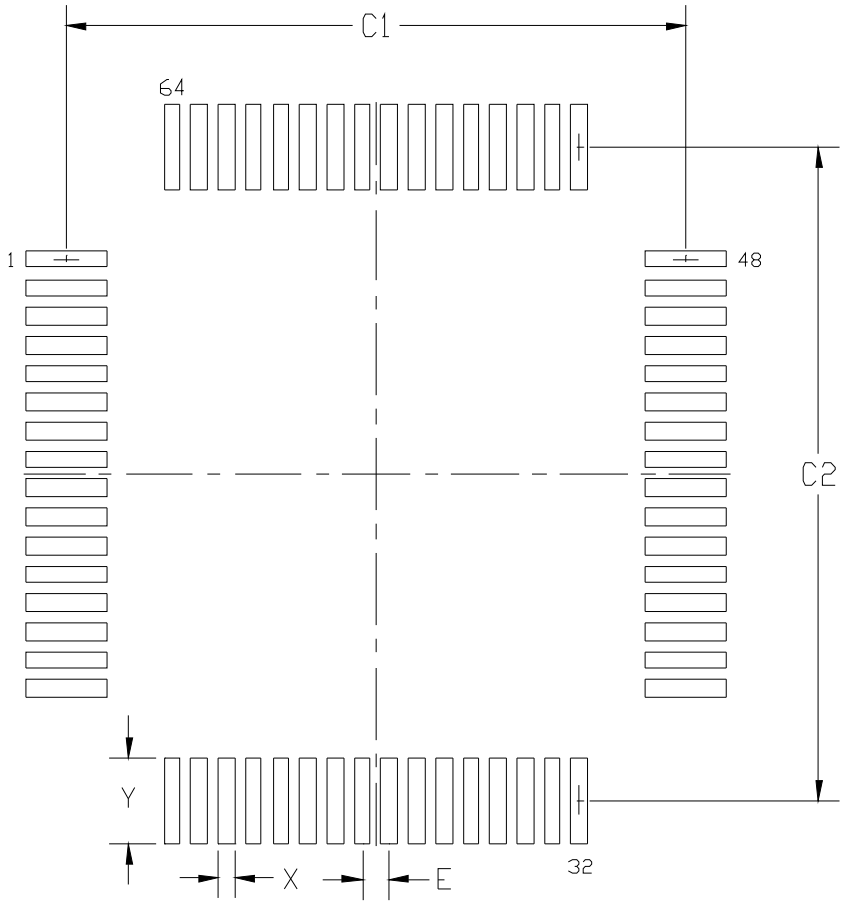

Figure 6.13. TQFP-64 Landing Diagram

Table 6.11. TQFP-64 Landing Diagram Dimensions

Dimension	Min	Max
C1	11.30	11.40
C2	11.30	11.40
E	0.50 BSC	
X	0.20	0.30
Y	1.40	1.50

Notes:
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This land pattern design is based on the IPC-7351 guidelines.

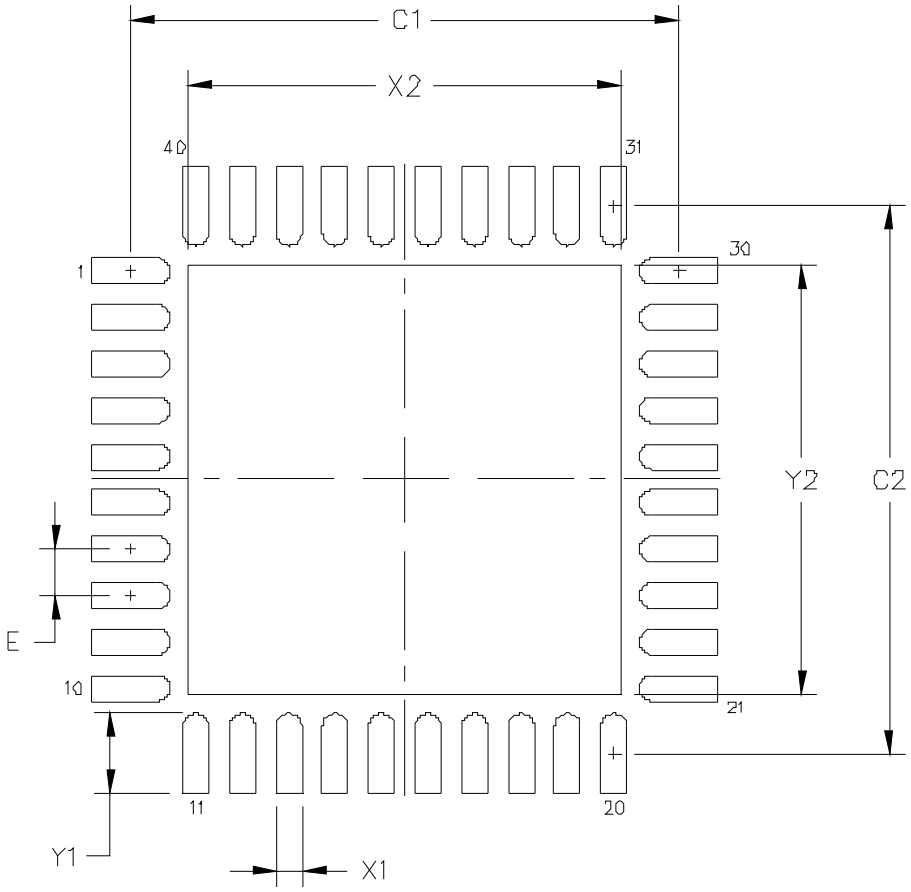

Figure 6.15. QFN-40 Landing Diagram

Table 6.13. QFN-40 Landing Diagram Dimensions

Dimension	mm
C1	5.90
C2	5.90
E	0.50
X1	0.30
Y1	0.85
X2	4.65
Y2	4.65

Notes:
1. All dimensions shown are in millimeters (mm).
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

7. Revision Specific Behavior

This chapter details any known differences from behavior as stated in the device datasheet and reference manual. All known errata for the current silicon revision are rolled into this section at the time of publication. Any errata found after publication of this document will initially be detailed in a separate errata document until this datasheet is revised.

7.1. Revision Identification

The Lot ID Code on the top side of the device package can be used for decoding device revision information. Figures 7.1, 7.2, 7.3, and 7.4 show how to find the Lot ID Code on the top side of the device package.

In addition, firmware can determine the revision of the device by checking the DEVICEID registers.

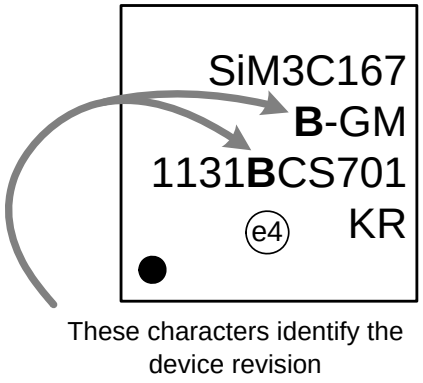

Figure 7.1. LGA-92 SiM3C1x7 Revision Information

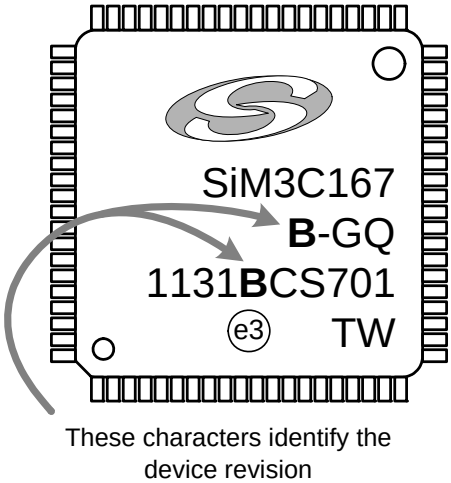

Figure 7.2. TQFP-80 SiM3C1x7 Revision Information